

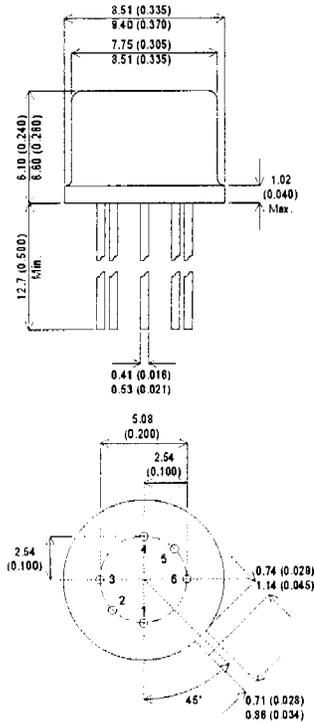
20 STERN AVE.  
 SPRINGFIELD, NEW JERSEY 07081  
 U.S.A.

TELEPHONE: (973) 376-2922  
 (212) 227-6005  
 FAX: (973) 376-8960

**MECHANICAL DATA**  
 Dimensions in mm (inches)

**2N2913**  
**2N2915**  
**2N2917**

**DUAL NPN  
 PLANAR TRANSISTORS IN  
 TO77 PACKAGE**



**TO-77 PACKAGE**

- PIN 1 – Collector 1
- PIN 2 – Base 1
- PIN 3 – Emitter 1
- PIN 4 – Emitter 2
- PIN 5 – Base 2
- PIN 6 – Collector 2

**ABSOLUTE MAXIMUM RATINGS**

		$(T_{amb} = 25^{\circ}\text{C unless otherwise stated})$	
		EACH SIDE	TOTAL DEVICE
$V_{CBO}$	Collector – Base Voltage	45V	
$V_{CEO}$	Collector – Emitter Voltage <sup>1</sup>	45V	
$V_{EBO}$	Emitter – Base Voltage	6V	
$I_C$	Continuous Collector Current	30	
$P_D$	Total Device Dissipation	$T_{AMB} = 25^{\circ}\text{C}$	300mW
		Derate above $25^{\circ}\text{C}$	1.72mW / $^{\circ}\text{C}$
$P_D$	Total Device Dissipation	$T_C = 25^{\circ}\text{C}$	500mW
		Derate above $25^{\circ}\text{C}$	1.72mW / $^{\circ}\text{C}$
$T_{STG}$	Storage Temperature Range	-65 to $200^{\circ}\text{C}$	
$T_L$	Lead temperature (Soldering, 10 sec.)	300 $^{\circ}\text{C}$	

**NOTES**

1. Base – Emitter Diode Open Circuited.

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## ELECTRICAL CHARACTERISTICS ( $T_{amb} = 25^{\circ}\text{C}$ unless otherwise stated)

Parameter	Test Conditions <sup>1</sup>	Min.	Typ.	Max.	Unit
<b>INDIVIDUAL TRANSISTOR CHARACTERISTICS</b>					
$V_{(BR)CBO}$	Collector – Base Breakdown Voltage	$I_C = 10\mu\text{A}$	$I_E = 0$	45	V
$V_{(BR)CEO^*}$	Collector – Emitter Breakdown Voltage	$I_C = 10\text{mA}$	$I_B = 0$	45	
$V_{(BR)EBO}$	Emitter – Base Breakdown Voltage	$I_E = 10\mu\text{A}$	$I_C = 0$	6	
$I_{CBO}$	Collector Cut-off Current	$V_{CB} = 45\text{V}$	$I_E = 0$	10	nA
			$T_A = 150^{\circ}\text{C}$	10	$\mu\text{A}$
$I_{CEO}$	Collector Cut-off Current	$V_{CE} = 5\text{V}$	$I_B = 0$	2	nA
$I_{EBO}$	Emitter Cut-off Current	$V_{EB} = 5\text{V}$	$I_C = 0$	2	
$h_{FE}$	DC Current Gain	$V_{CE} = 5\text{V}$	$I_C = 10\mu\text{A}$	60	—
			$T_A = -55^{\circ}\text{C}$	15	
		$V_{CE} = 5\text{V}$	$I_C = 100\mu\text{A}$	100	
		$V_{CE} = 5\text{V}$	$I_C = 1\text{mA}$	150	
$V_{BE}$	Base – Emitter Voltage	$V_{CE} = 5\text{V}$	$I_C = 100\mu\text{A}$	0.70	V
$V_{CE(sat)}$	Collector – Emitter Saturation Voltage	$I_B = 100\mu\text{A}$	$I_C = 1\text{mA}$	0.35	
$h_{ib}$	Small Signal Common – Base Input Impedance	$V_{CB} = 5\text{V}$	$I_C = 1\text{mA}$	25	$\Omega$
		$f = 1\text{kHz}$		32	
$h_{ob}$	Small Signal Common – Base Output Admittance	$V_{CB} = 5\text{V}$	$I_C = 1\text{mA}$	1	$\mu\text{mho}$
		$f = 1\text{kHz}$			
$ h_{fe} $	Small Signal Common – Base Current Gain	$V_{CE} = 5\text{V}$	$I_C = 500\mu\text{A}$	3	—
		$f = 20\text{MHz}$			
$C_{obo}$	Common – Base Open Circuit Output Capacitance	$V_{CB} = 5\text{V}$	$I_E = 0$	6	pF
		$f = 140\text{kHz to } 1\text{MHz}$			

\* Pulse Test:  $t_p = 300\mu\text{s}$ ,  $\delta \leq 1\%$ .

Parameter	Test Conditions	2N2915			2N2917			Unit
		Min.	Typ.	Max.	Min.	Typ.	Max.	
<b>TRANSISTOR MATCHING CHARACTERISTICS</b>								
$h_{FE1}$	Static Forward Current	$V_{CE} = 5\text{V}$	$I_C = 100\mu\text{A}$	0.9	1	0.8	1	—
$h_{FE2}$	Gain Balance Ratio	See Note 2.						
$ V_{BE1} - V_{BE2} $	Base – Emitter Voltage Differential	$V_{CE} = 5\text{V}$	$I_C = 100\mu\text{A}$		3		5	mV
		$V_{CE} = 5\text{V}$	$I_C = 10\mu\text{A to } 1\text{mA}$		5		10	
$ \Delta(V_{BE1} - V_{BE2})/\Delta T_A $	Base – Emitter Voltage Differential Change With Temperature	$V_{CE} = 5\text{V}$	$I_C = 100\mu\text{A}$		0.8		1.6	mV
		$T_{A1} = 25^{\circ}\text{C}$	$T_{A2} = -55^{\circ}\text{C}$					
		$V_{CE} = 5\text{V}$	$I_C = 100\mu\text{A}$		1		2	
		$T_{A1} = 25^{\circ}\text{C}$	$T_{A2} = 125^{\circ}\text{C}$					

### NOTES

- 1) Terminals not under test are open circuited under all test conditions.
- 2) The lower of the two readings is taken as  $h_{FE1}$ .